

General Description

The WSF3013C is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density, which provide excellent R_{DS(on)} and gate charge for most of the synchronous buck converter applications.

The WSF3013C meet the RoHS and Green Product requirement 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

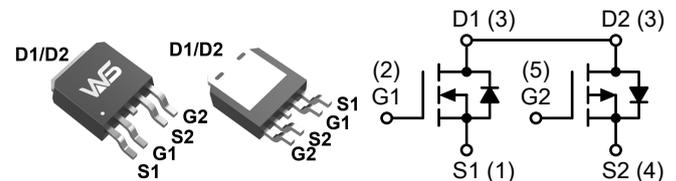
Product Summary

BVDSS	R _{DS(on)}	I _D
30V	15mΩ	25A
-30V	36mΩ	-18A

Applications

- BLDC
- DC-DC Power System

TO-252-4L Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-Ch	P-Ch	
V _{DS}	Drain-Source Voltage	30	-30	V
V _{GS}	Gate-Source Voltage	±20	±20	V
I _D	Continuous Drain Current, V _{GS(NP)} =10V, T _c =25°C	25	-18	A
	Continuous Drain Current, V _{GS(NP)} =10V, T _c =100°C	10	-10	A
I _{DP} ^a	Pulse Drain Current Tested, V _{GS(NP)} =10V	60	-50	A
E _{AS} ^c	Avalanche Energy, Single pulse, L=0.5mH	22	45	mJ
I _{AS} ^c	Avalanche Current, Single pulse, L=0.5mH	21	-30	A
P _D	Total Power Dissipation, T _c =25°C	25	25	W
T _{STG}	Storage Temperature Range	-55 to 150	-55 to 150	°C
T _J	Operating Junction Temperature Range	150	150	°C
R _{θJA} ^b	Thermal Resistance-Junction to Ambient, Steady State	60	60	°C/W
R _{θJC}	Thermal Resistance-Junction to Case, Steady State	5.1	5.1	°C/W

Note * : Max. current is limited by bonding wire.

Note a : Pulse width limited by max. junction temperature.

Note b : R_{θJA} steady state t=999s. R_{θJA} is measured with the device mounted on 1in², FR-4 board with 2oz. Copper.

Note c : UIS tested and pulse width limited by maximum junction temperature 150°C (initial temperature T_J=25°C).

N-Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	30	---	---	V
R _{DS(ON)} ^d	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =10A	---	15	25	mΩ
		V _{GS} =4.5V, I _D =5A	---	24	40	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.0	1.6	2.5	V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =20V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =20V, V _{GS} =0V, T _J =85°C	---	---	30	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	2.3	5.0	Ω
Q _g ^e	Total Gate Charge	V _{DS} =20V, V _{GS} =4.5V, I _{DS} =1A	---	7.2	---	nC
Q _{gs} ^e	Gate-Source Charge		---	1.4	---	
Q _{gd} ^e	Gate-Drain Charge		---	2.2	---	
T _{d(on)} ^e	Turn-On Delay Time	V _{DD} =12V, I _{DS} =5A, V _{GS} =10V, R _G =3.3R.	---	4.1	---	ns
T _r ^e	Rise Time		---	9.8	---	
T _{d(off)} ^e	Turn-Off Delay Time		---	15.5	---	
T _f ^e	Fall Time		---	6.0	---	
C _{iss} ^e	Input Capacitance	V _{DS} =15V, V _{GS} =0V, f=1MHz	---	611	---	pF
C _{oss} ^e	Output Capacitance		---	85	---	
C _{rss} ^e	Reverse Transfer Capacitance		---	67	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I _S	Continuous Source Current	V _G =V _D =0V, Force Current	---	---	25	A
V _{SD} ^d	Diode Forward Voltage	V _{GS} =0V, I _S =1A	---	---	1.2	V

Note d : Pulse test ; pulse width≤300μs, duty cycle≤2%.

Note e : Guaranteed by design, not subject to production testing.

P-Channel Electrical Characteristics ($T_J=25\text{ }^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30	---	---	V
$R_{DS(ON)}^d$	Static Drain-Source On-Resistance	$V_{GS}=-10V, I_D=-4.0A$	---	36	42	m Ω
		$V_{GS}=-4.5V, I_D=-3.0A$	---	52	60	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.2	-1.7	-2.5	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=-24V, V_{GS}=0V, T_J=25^\circ C$	---	---	-1	μA
		$V_{DS}=-24V, V_{GS}=0V, T_J=85^\circ C$	---	---	-30	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	± 100	nA
Q_g^e	Total Gate Charge	$V_{DS}=-20V,$ $V_{GS}=-4.5V,$ $I_D=-4A$	---	9.2	---	nC
Q_{gs}^e	Gate-Source Charge		---	2.0	---	
Q_{gd}^e	Gate-Drain Charge		---	3.1	---	
$T_{d(on)}^e$	Turn-On Delay Time	$V_{DD}=-24V, I_D=-1A, R_L=15\Omega,$ $V_{GS}=-10V, R_G=3.3\Omega.$	---	15	---	ns
T_r^e	Rise Time		---	19	---	
$T_{d(off)}^e$	Turn-Off Delay Time		---	53	---	
T_f^e	Fall Time		---	9	---	
C_{iss}^e	Input Capacitance	$V_{DS}=-15V, V_{GS}=0V, f=1MHz$	---	910	---	pF
C_{oss}^e	Output Capacitance		---	141	---	
C_{rss}^e	Reverse Transfer Capacitance		---	98	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Source Current	$V_G=V_D=0V$, Force Current	---	---	-18	A
V_{SD}^e	Diode Forward Voltage	$V_{GS}=0V, I_S=-1A, T_J=25^\circ C$	---	---	-1.2	V

Note d : Pulse test; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

Note e : Guaranteed by design, not subject to production testing.

N-Channel Typical Characteristics

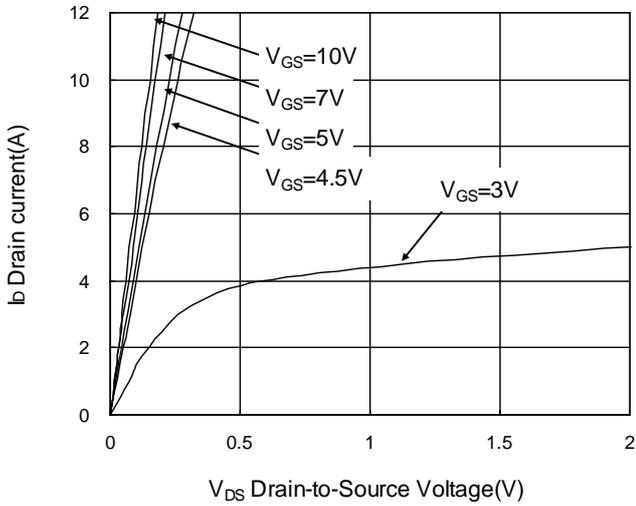


Fig.1 Typical Output Characteristics

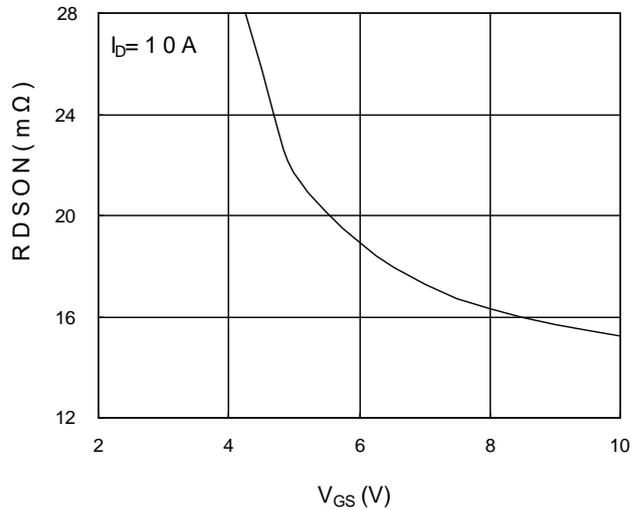


Fig.2 On-Resistance v.s Gate-Source

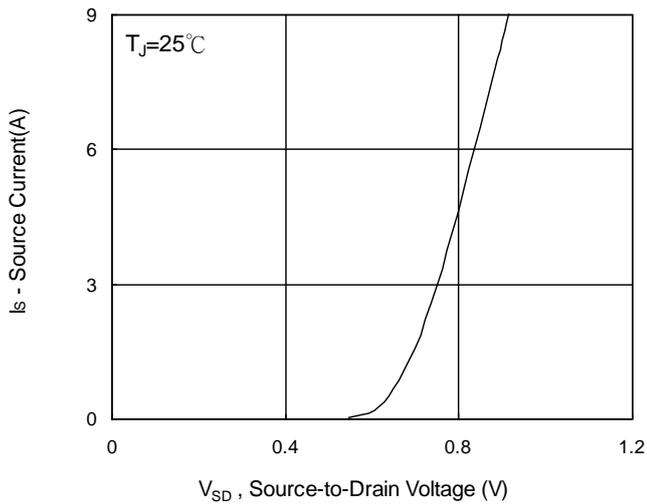


Fig.3 Forward Characteristics Of Reverse

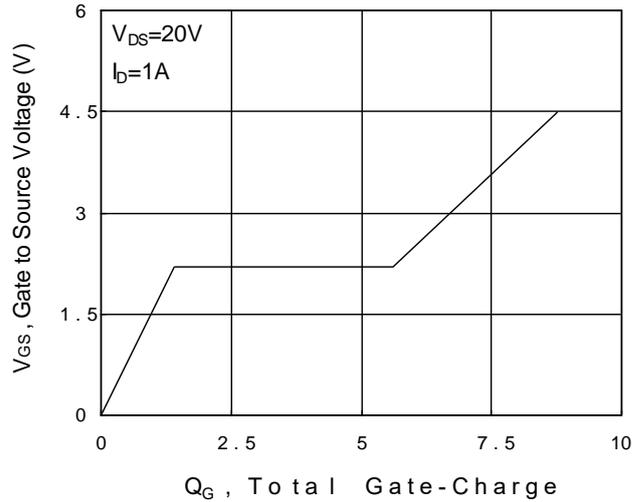


Fig.4 Gate-Charge characteristics

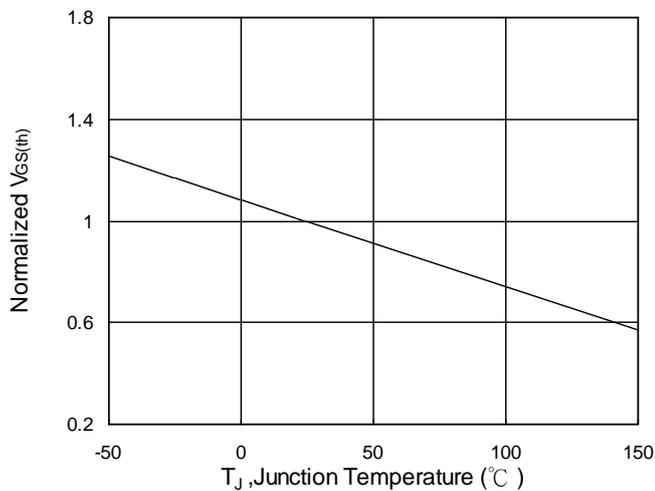


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

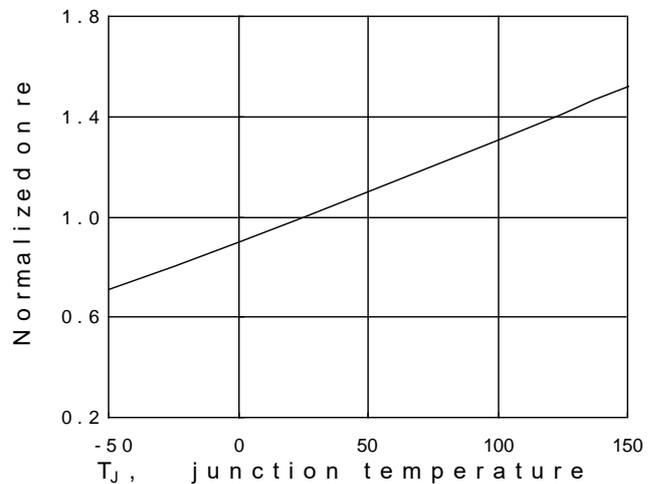


Fig.6 Normalized $R_{DS(on)}$ v.s T_J

N-Channel Typical Characteristics

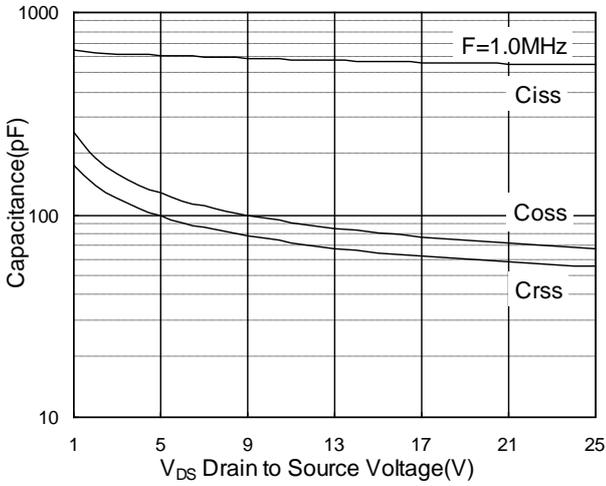


Fig.7 Capacitance

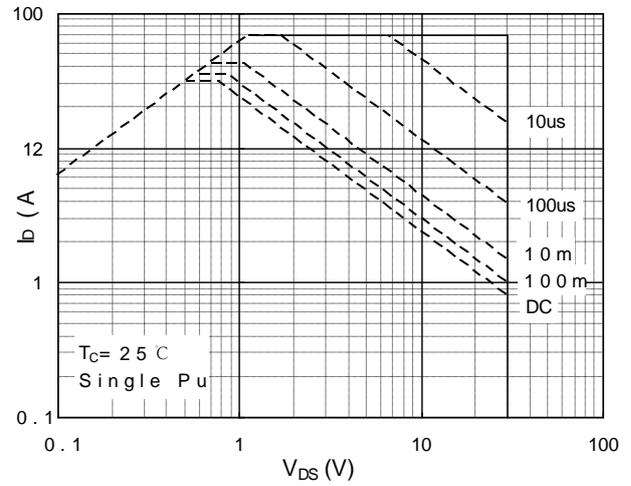


Fig.8 Safe Operating Area

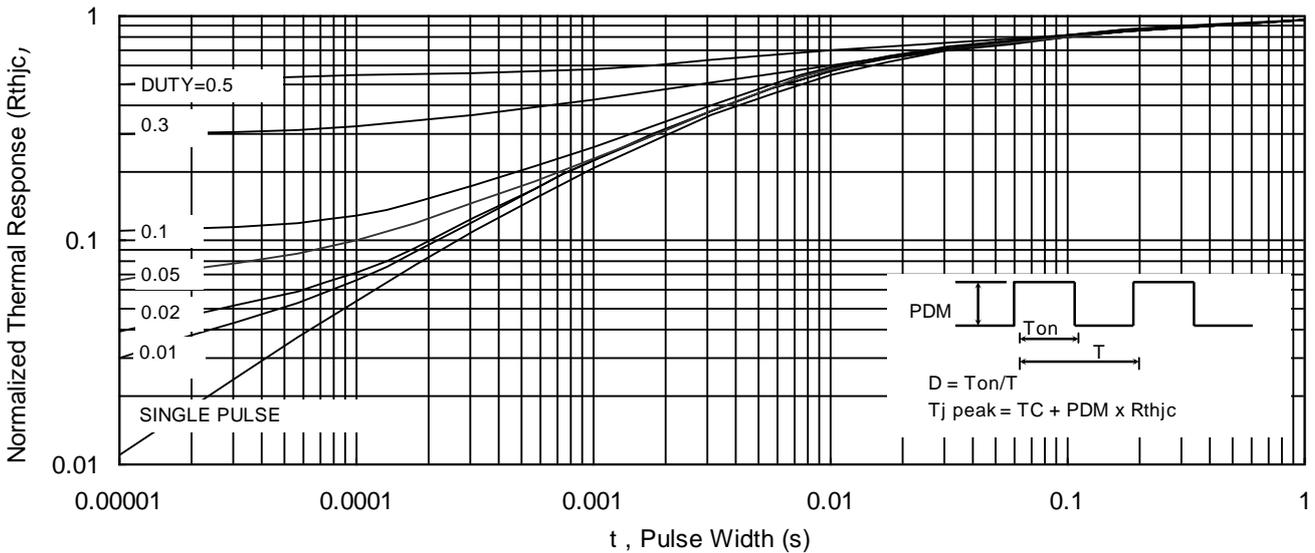


Fig.9 Normalized Maximum Transient Thermal Impedance

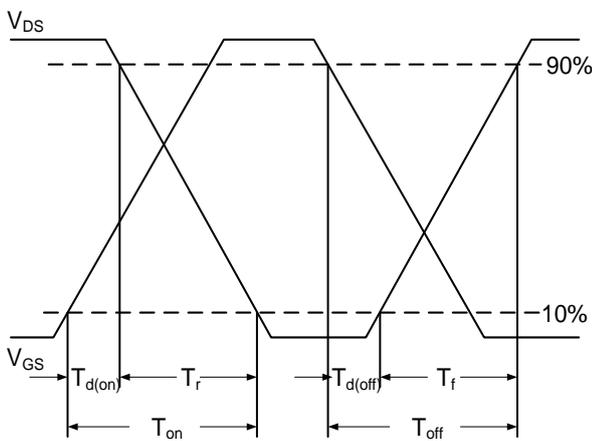


Fig.10 Switching Time Waveform

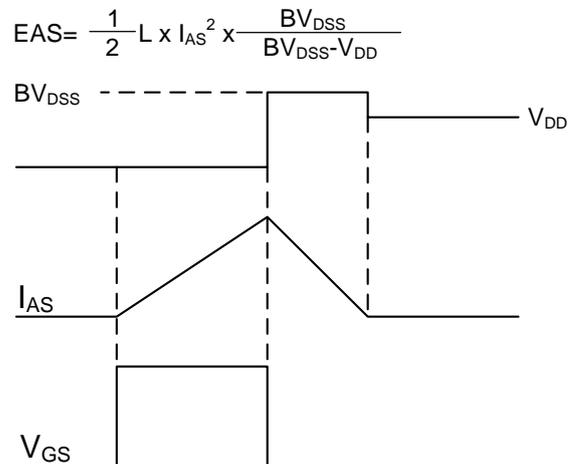


Fig.11 Unclamped Inductive Waveform

P-Channel Typical Characteristics

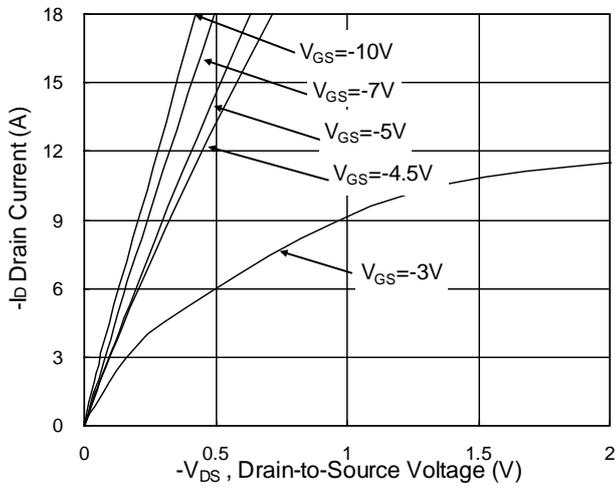


Fig.1 Typical Output Characteristics

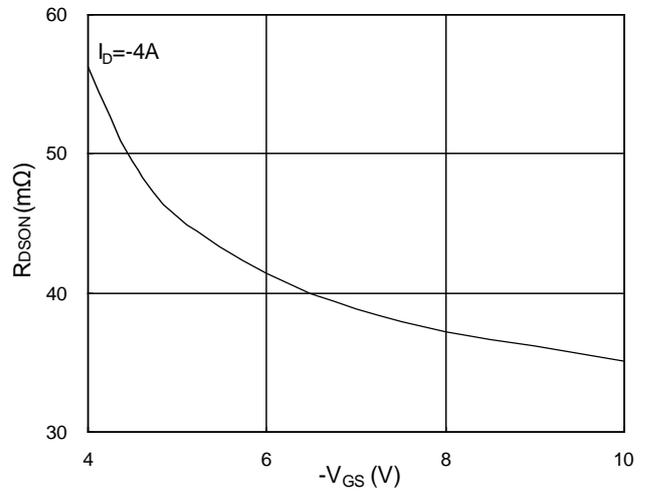


Fig.2 On-Resistance v.s Gate-Source

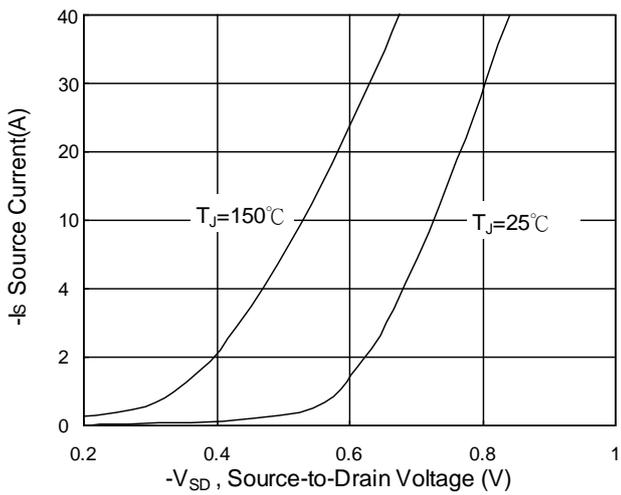


Fig.3 Forward Characteristics of Reverse

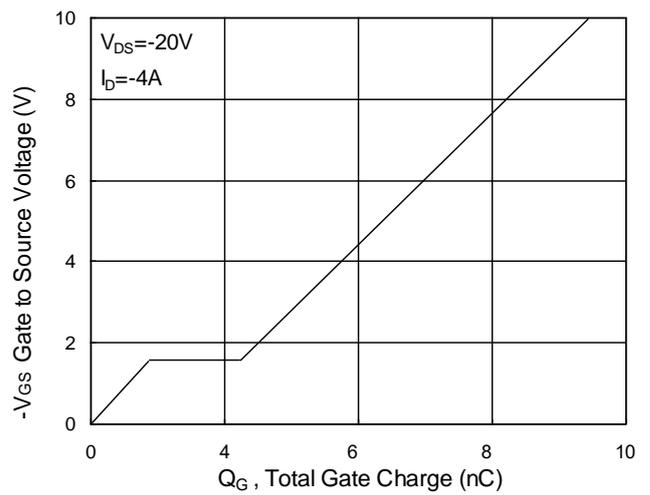


Fig.4 Gate-Charge Characteristics

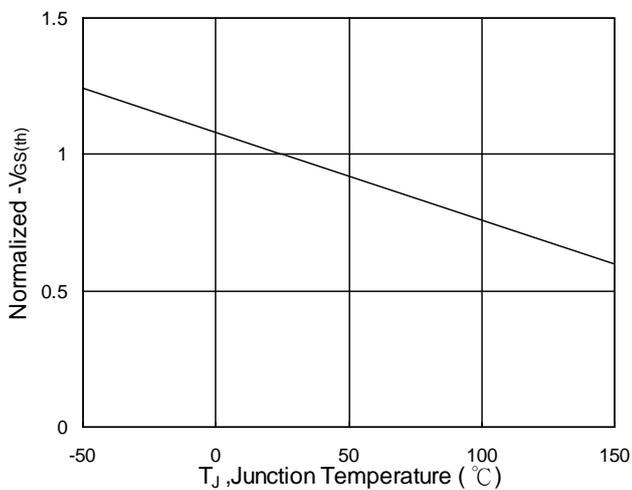


Fig.5 Normalized V_{GS(th)} v.s T_J

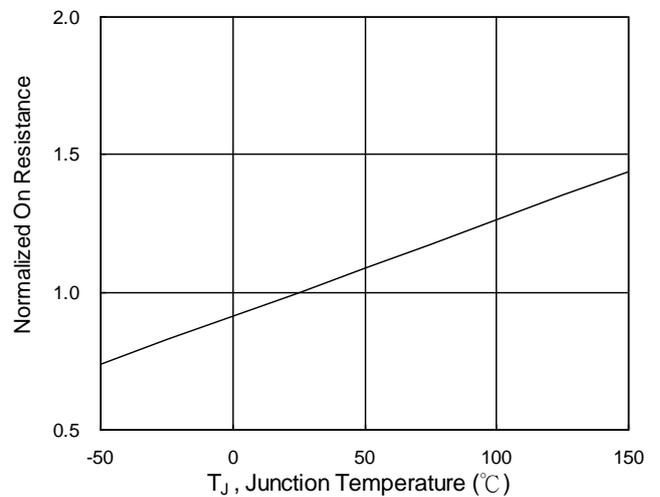


Fig.6 Normalized R_{DS(on)} v.s T_J

P-Channel Typical Characteristics

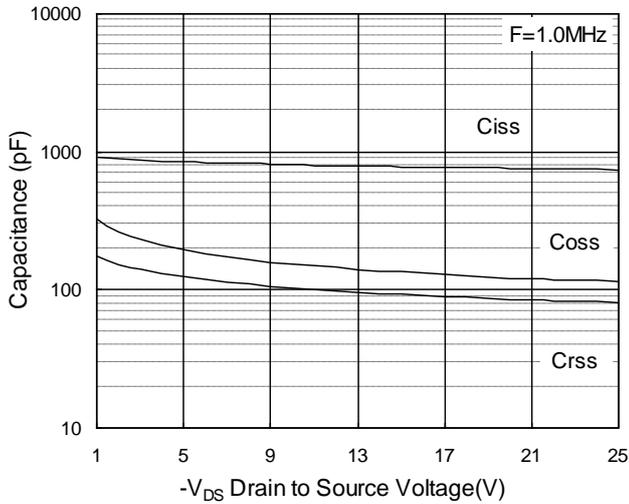


Fig.7 Capacitance

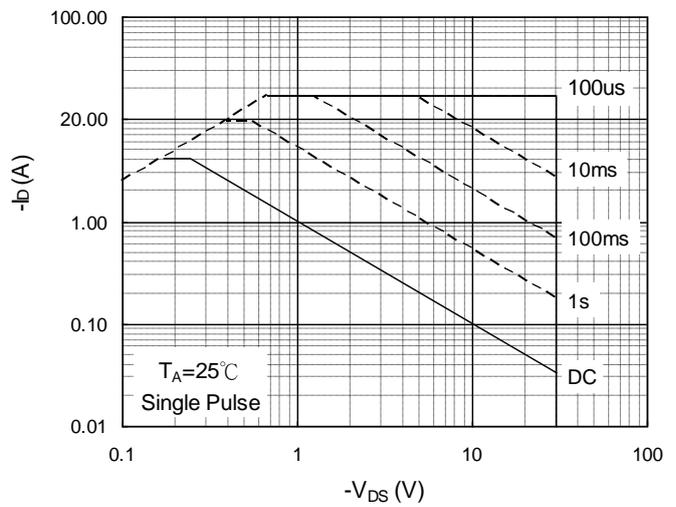


Fig.8 Safe Operating Area

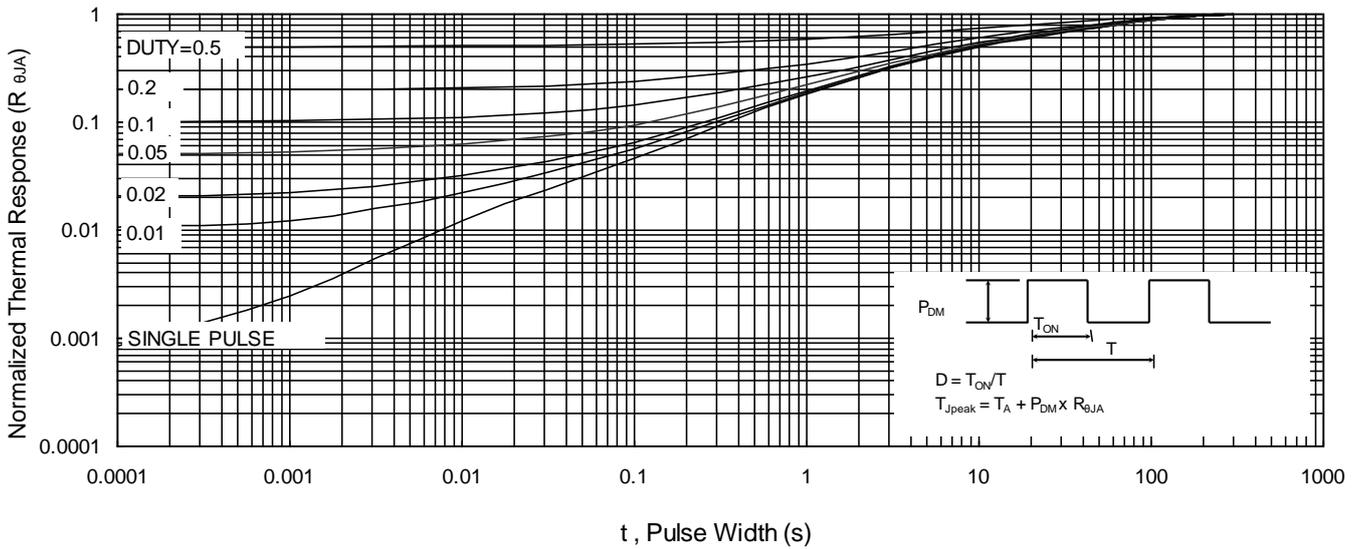


Fig.9 Normalized Maximum Transient Thermal Impedance

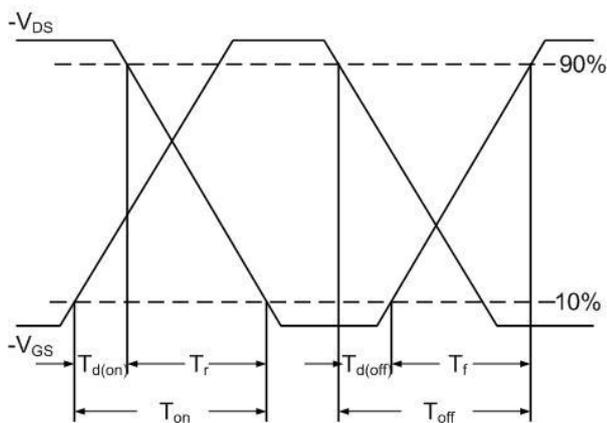


Fig.10 Switching Time Waveform

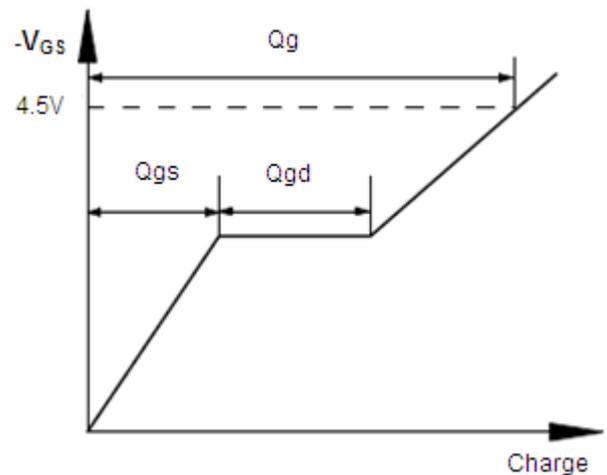
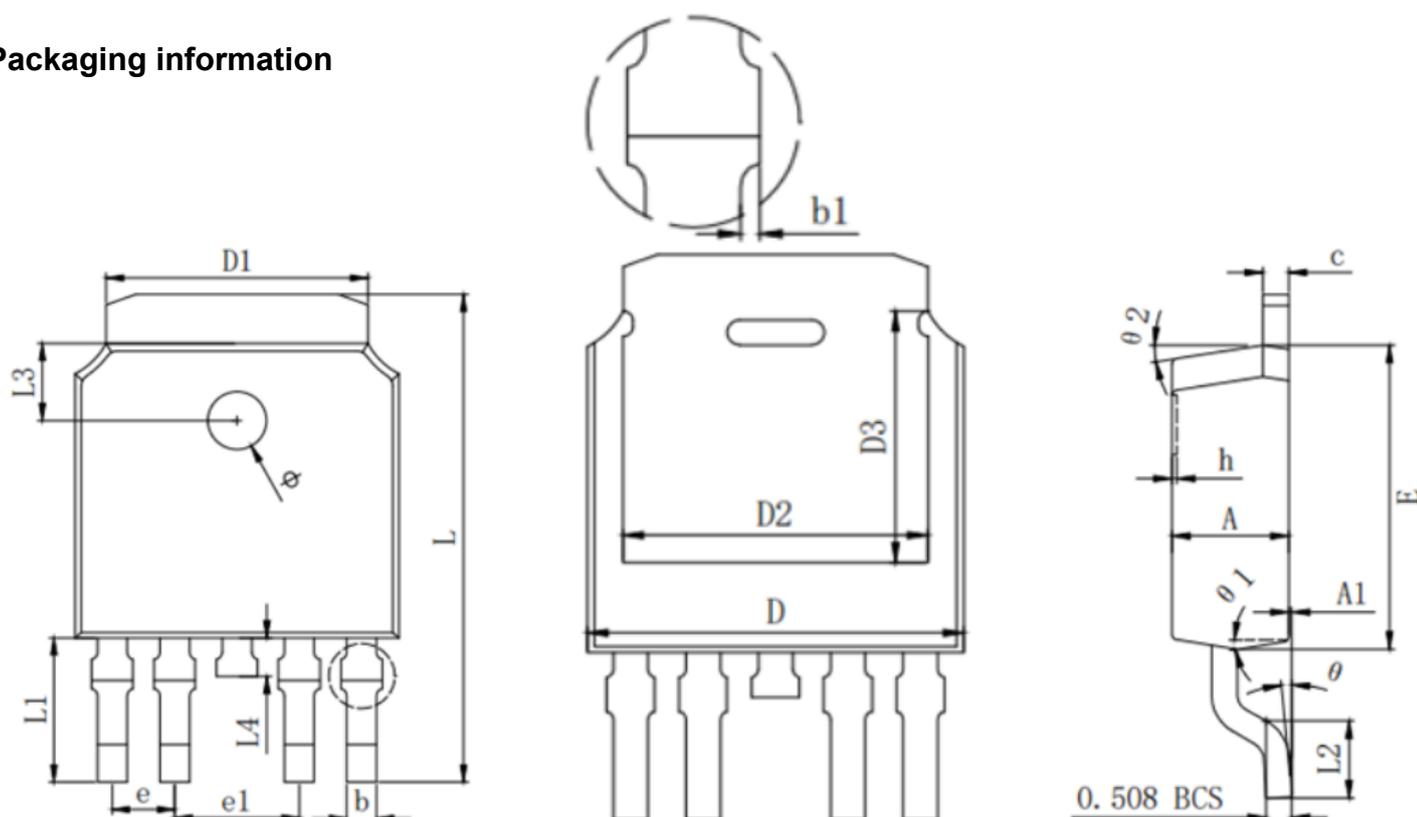


Fig.11 Gate Charge Waveform

Packaging information


SYMBOLS	MILLIMETERS		
	MIN.	Typ.	MAX.
A	2.200	2.300	2.400
A1	0.000	-	0.127
b	0.550	0.600	0.650
b1	0.000	-	0.120
c(电镀后)	0.460	0.520	0.580
D	6.500	6.600	6.700
D1	5.334 REF		
D2	5.346 REF		
D3	4.490 REF		
E	6.000	6.100	6.200
e	1.270 TYP		
e1	2.540 TYP		
h	0.000	0.100	0.200
L	9.900	10.100	10.300
L1	2.988 REF		
L2	1.400	1.550	1.700
L3	1.600 REF		
L4	0.700	0.800	0.900
φ	1.100	1.200	1.300
θ	0°	-	8°
θ 1	9° TYP		
θ 2	9° TYP		



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